

GEM IV

Bench Top Automated Optical Inspection for SMT Inspection



GEM IV

The **GEM IV** AOI system features a revolutionary small, lightweight inspection solution that is flexible for SPI, Pre-Reflow, Post-Reflow or Post-Wave inspection.

Accommodating boards up to 10" x 15" the GEM IV now offers unsurpassed, high-performance and high-resolution capabilities previously only available with MVP's existing in-line systems. With standard Z-Axis and high-resolution optics, the GEM IV represents a breakthrough in tabletop inspection by providing comprehensive solutions to complex inspection challenges.

Footprint: (W x L x H)	- 14" x 30" x 25" (609 x 762 x 635 mm)
Board Dimensions (W x L)	- 10" x 15"
Power	- 100-240V, 50/60 Hz
Weight	- 125lbs (57kg)

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Key Features

- Tabletop AOI with In-line Performance
- 12mp Camera with Z-Lift
- Portable Configuration
- Multi-Tier Lighting
- Ideal for High Mix or NPI
- Easy-To-Use, Award Winning iPro and ePro Software
- Component Inspection Pre/Post Reflow
- Program Compatibility with In-line Systems

